

Agenda

updated: August 29, 2017

17th October (Tue)	12:00 - 14:00	<i>Registration /Lunch</i>				
	14:00 - 14:20	Introduction				
	Session 1: Interferometry and calibration of length standards, Part 1 Session Chair: Andrew Lewis, NPL					
	14:20 - 14:45	#38_2017	High accuracy interferometer for step gauge calibration	Antti Lassila	VTT MIKES	Finland
	14:45 - 15:10	#15_2017	Phase and roughness correction for interferometric measurement of gauge blocks	Petr Balling	CMI	Czech Republic
	15:10 - 15:35	#09_2017	Dispersion-based refractivity compensation in realistic conditions: case studies from surveying and industrial applications	Florian Pollinger	PTB	Germany
	15:35 - 16:00	#22_2017	Measurement of the refractive index of diluted air and comparison with values obtained from an empirical formula	René Schödel	PTB	Germany
	16:00 - 18:00	<i>Reception / Lab visits</i>				

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18th October (Wed)

Session 2: Interferometry and calibration of length standards, Part 2

Session Chair: Michael Matus, BEV

09:00 - 09:25	#17_2017	Evaluation of long-term stability of low thermal expansion coefficient materials by gauge block interferometers	Akiko Hirai	NMIJ	Japan
09:25 - 09:50	#34_2017	Optical simulation of the influence of real topographies on the result of the volume of PTB spheres	Eva Kuhn	PTB	Germany
09:50 - 10:15	#24_2017	Line width calibration with the Automatic Interference Comparator Lambda-Mess 600	Chris Schuchardt	Carl Zeiss Jena	Germany
10:15 - 10:40	#43_2017	Voice coil based actuator with interferometric position feedback for the sub-nanometre range	Gabor Molnar	PTB	Germany

10:40 - 12:10 *Coffee Break / Poster Session I*

12:10 - 13:10 *Lunch*

Session 3: Evaluation of measuring methods and measurement uncertainty

Session Chair: Rudolf Thalmann, METAS

13:10 - 13:35	#37_2017	The Potential Roles of Frequency Measurement in EDM Calibration	Lucy Forde	MSL	New Zealand
13:35 - 14:00	#08_2017	Arpent: a new high accuracy long-range Absolute Distance Meter	Joffray Guillory	LNE	France

Session 4: Coordinate metrology

Session Chair: Oelof Kruger, NMISA

14:00 - 14:25	#10_2017	Measuring the geometry of a dimensional computed tomography (CT) system	Benjamin Bircher	METAS	Switzerland
14:25 - 14:50	#28_2017	Interferometric step gauge for CMM verification	Björn Hemming	VTT MIKES	Finland
14:50 - 15:15	#44_2017	Experimental study on capture efficiency of length measurement error sparsely performed on optical 3D coordinate measuring systems based on two dimensional image projection	Makoto Abe	NMIJ	Japan

15:15 - 16:45 *Coffee Break / Poster Session II*

20:00 *Conference Dinner*

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19th October (Thu)	Session 5: Form and angle metrology					
	Session Chair: José-Antonio Salgado, LNE					
	09:00 - 09:25	#19_2017	Investigations of interpolation errors of angle encoders for high precision angle metrology	Tanfer Yandayan	UME	Turkey
	09:25 - 09:50	#26_2017	Interferometric 2D small angle generator	Ville Heikkinen	VTT MIKES	Finland
	09:50 - 10:15	#07_2017	Four-point form measurement of small spheres	Rudolf Thalmann	METAS	Switzerland
	10:15 - 10:40	#18_2017	Scanning Deflectometric Profiler (SDP) systems at NMIJ	Youichi Bitou	NMIJ	Japan
	10:40 - 11:00		<i>Coffee Break</i>			
	Session 6: Surface texture measurements					
	Session Chair: Rainer Koenig, PTB					
	11:00 - 11:25	#16_2017	A hybrid 2D/3D inspection concept with smart routing optimisation for high throughput, high dynamic range and traceable critical dimension metrology	Christopher W Jones	NPL	UK
	11:25 - 11:50	#27_2017	Traceable measurements of rounded cutting tool edges	Felix Meli	METAS	Switzerland
11:50 - 12:15	#47_2017	Design of Metrological White Light Interference System with Dynamic Reconstitution Algorithm	Yushu Shi	NIM	China	
12:15 - 14:00		<i>Closing / Lunch / Discussions</i>				

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Poster Session I

#01_2017	Evaluation of geometrical parameters of workpieces in serial production under harsh environmental conditions by referring to calibrated reference parts	Dmytro Sumin	Technical University of Braunschweig	Germany
#02_2017	Calibration of a 400 mm helical master gear at INRIM	Alessandro Balsamo	INRIM	Italy
#03_2017	Clamping of microgears with a compliant string	Stephan Jantzen	PTB	Germany
#04_2017	Areal and traceable measurement strategy for the calibration of thread parameters with a coordinate measuring machine	Sebastian Schädel	PTB	Germany
#05_2017	A single-comb source for heterodyne dual-comb multi-wavelength interferometry	Pengfei Cui	PTB	Germany
#06_2017	Versatile calibration artefact for optical micro-CMMs based on micro-spheres with engineered surface texture	Rudolf Thalmann	METAS	Switzerland
#11_2017	Super-resolution frequency estimation for frequency modulated continuous-wave laser ranging using subspace decomposition methods	Pan Hao	Tianjin University	China
#12_2017	NPL ULTIMUM ⁺ – design of a generic 1-D measuring machine to deliver a broad range of dimensional calibration	Sean Woodward	NPL	UK
#13_2017	Two methods for precise determination of the diffraction correction of Gaussian beams in interferometers	Petr Kren	CMI	Czech Republic
#14_2017	Confocal chromatic line sensors: characterization with different surfaces and in-situ calibration	Jeremias Seppä	VTT MIKES	Finland
#20_2017	New Modular 10m-Bench System for Traceable Measurements of Tapes And Rules At TUBITAK UME	Bulent Ozgur	UME	Turkey
#21_2017	Upgrade of 5m-Bench System for Traceable Measurements of Tapes and Rules at SASO-NMCC Dimensional Laboratory	Bulent Ozgur	UME	Turkey
#23_2017	Long Range Displacement Measurements using FM Modulated Laser	Mehmet Çelik	UME	Turkey

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Poster Session II

#25_2017	Multi sensor optical profilometer for measurement of freeform surfaces	Ville Heikkinen	VTT MIKES	Finland
#29_2017	Multi-dimensional grating interferometer based on fibre-fed heads arranged in Littrow configuration	Lauryna Siaudinyte	PTB	Germany
#30_2017	Scatterometric method for online optical fibre geometry measurement	Maksim Shpak	VTT MIKES	Finland
#31_2017	Integration of a step gauge measurement capability at the PTB Nanometer Comparator	Christoph Weichert	PTB	Germany
#32_2017	Uncertainty Evaluation of an Optical Wafer Thickness Measuring System	Chu-Shik Kang	KRISS	South Korea
#33_2017	The evolution of measurements of graduated scales at the Nanometer Comparator at PTB	Rainer Köning	PTB	Germany
#36_2017	Metrological set-up for calibrating 2D grid plates with sub-micrometre precision	Rok Klobucar	UM	Slovenia
#39_2017	Evaluation of measuring methods for the evaluation of Additive Manufacturing	Oelof Kruger	NMISA	South Africa
#40_2017	INTI Kösters-Comparator recovery. Interferometric measurement validation for 100 mm and 300 mm	Karina Bastida	INTI	Argentina
#41_2017	Stability of XCT measurements with different (W, Mo, Cu, and Ag) X-ray target material	Marko Katic	University of Zagreb	Croatia
#42_2017	Virtual CMM – for correcting errors and uncertainty determination	Ville Heikkinen	VTT MIKES	Finland
#46_2017	Morphology-driven parameters of engineered functional surfaces	Gian Bartolo Picotto	INRIM	Italy